Search Notes			
	INTRI ERITH FI	ALU 18110 (BII)	

Application/Control No.	Applicant(s)/Patent under Reexamination
09/829,961	TAVOR, ONN
Examiner	Art Unit
Thomas E. Shortledge	2654

	SEARCHED			
Class	Subclass	Date	Examiner	
<u>.</u>				
	<del></del>			

ראו	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
			·		
	İ				

(INCLUDING SEARCH STRATEGY)			
·	DATE	EXMR	
ACL Anothology search "sentence emplate" "sentence creation"	6/23/2005	TS	